


<b>Search Notes</b> 	<b>Application/Control No.</b> 10553501	<b>Applicant(s)/Patent Under Reexamination</b> LEE, BAEK-WOON
	<b>Examiner</b> MY-CHAU T TRAN	<b>Art Unit</b> 2629

SEARCHED			
Class	Subclass	Date	Examiner
345	55, 84, 87, 88, 90, 92, 93, 103	12/18/2008	MCT

SEARCH NOTES		
Search Notes	Date	Examiner
PALM Inventor; WEST - see printout	12/18/2008	MCT
Reviewed for ODP the following Patent(s) and/or Application(s): 11/224,038	12/18/2008	MCT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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